

PSE Technology Corporation

SPECIFICATION FOR APPROVAL

CUSTOMER	
NOMINAL FREQUENCY	32.768 KHz
PRODUCT TYPE	TYPE G8 SMD CRYSTAL
SPEC. NO. (P/N)	G83270025
CUSTOMER P/N	
ISSUE DATE	Jun.16,2016
VERSION	Α

APPROVED	PREPARED	QA
Brenda	Clane	Dong Jang
APPROVED BY	APPROVED BY CUSTOMER:	
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E0-R-4-014 Rev. E Page i

G83270025

VER. A 16-Jun-16

VERSION HISTORY

Version No.	Version Date	Customer Receipt Date	Supplier Receipt Date	Description	Notes
Α	Jun.16,2016			Initial Release	

E0-R-4-014 Rev. E

G83270025

VER. A 16-Jun-16

ELECTRICAL SPECIFICATIONS

SRe Part Number: G83270025

Parameters	Symbol	Specifications	Units	Notes
Nominal Frequency	Fn	32.768	KHz	
Frequency Tolerance	FT	± 20	ppm	at 25°C ± 5°C
Load Capacitance	CL	9	pF	Тур.
Drive Level	DL	0.1 / 0.5	μW	Typ. / Max.
Equivalent Series Resistance	ESR	70	ΚΩ	Max.
Temperature Coefficient	K	-0.03	ppm/°C ²	± 0.01ppm/°C ²
Operating Temperature Range	TR	-40 to 85	°C	
Shunt Capacitance	C0	1.5	pF	Тур.
Motional Capacitance	C1	6.5	fF	Тур.
Quality Factor	Q	13	K	Min.
Aging		± 3	ppm	Max. 1st year
Storage Temperature Range		-40 to 85	°C	
Insulation Resistance		500	МΩ	Min.

Reliability (Mechanical and environmental performances)

No.	Test Items	Conditions	Requirements
1	Bending test	Apply pressure in the direction of the arrow at a rate of about 0.5mm/s until bent width reaches 5mm, and hold for 30 seconds.	Without mechanical damage such as breaks and satisfy sealing specification. Frequency change: Within ±5ppm
2	Shear test	Apply 20N(2.04kgf) static load to the core of quartz crystal units in the direction of the arrow using a R0.5 scratch tool, then hold for 5 seconds.	Equivalent series resistance(E.S.R) change: Within 5kΩ
	Core body strength	Apply 10N(1.02kgf) static load to the quartz crystal units center in the direction of the arrow using a R0.5 pushing tool, then hold for 10 seconds.	
4	Vibration	Frequency sweep method shall be applied as follows. Quartz crystal units shall be vibrated with the sweeping frequency from 10Hz to 55Hz and return to 10Hz in 1 minute, with 1.5mm amplitude. This vibration shall be applied for 2 hours in each 3 perpendicular axes. Other procedures conform to JIS C 60068-2-6.	
5	Shock	Quartz crystal units shall be accelerated at 9810m/s2 by 1ms pulse duration. This shock shall be applied 3 times in each 3 perpendicular axes. Other procedures conform to JIS C 60068-2-27.	

G83270025

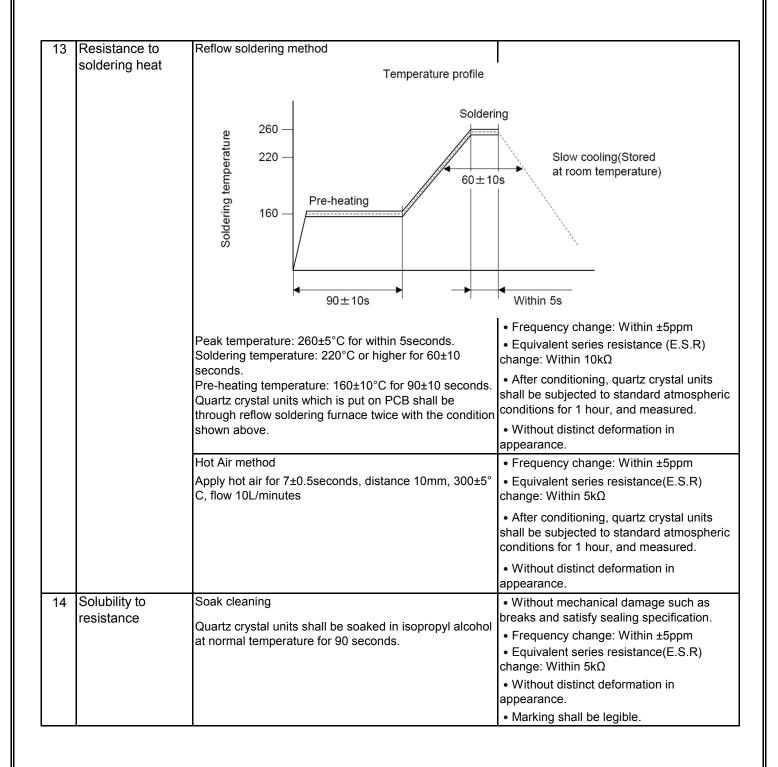
VER. A 16-Jun-16

6	Cold	Quartz crystal units shall be stored in the -40±3 $^{\circ}$ C atmosphere for 1000 hours. Other procedures conform to JIS C 60068-2-1. • Frequency change: Within ±5ppm • Equivalent series resistance(E.S.R) change: Within 5k Ω
7	Dry heat	Quartz crystal units shall be stored in the 100±2°C atmosphere for 100 hours. Other procedures conform to JIS C 60068-2-2. • After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured.
8	Damp heat	Quartz crystal units shall be stored in the $40\pm2^{\circ}$ C atmosphere with 90 to 95% relative humidity for 1000 hours. Other procedures conform to JIS C 60068-2-3.
9	Change of temperature	Quartz crystal units shall be subjected successively 100 cycles of temperature change shown below. Other procedures conform to JIS C 0025.
		Temperature Duration 1 -40±3°C 30min. 2 Normal temperature Within 30 sec. 3 100±2°C 30min. 4 Normal temperature Within 30 sec.
10 Sealing		Both the test methods specified below shall be applied. Quartz crystal units shall be soaked in 90°C or higher temperature hot water for 5 minutes. Quartz crystal units shall be tested by Mass • Without repetitive leaking bubbles from quartz crystal units. • 1×10-9 Pa·m3/s or less
		Quartz crystal units shall be tested by Mass spectrometric leakage detector to measure the leakage rate of helium gas.
11	Aging	 Quartz crystal units shall be stored in the 85±3°C atmosphere for 720±12 hours. Frequency change: Within ±5ppm Equivalent series resistance(E.S.R) change: Within 5kΩ After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured.
12	Solder-ability	Terminals coated with flux shall be immersed in the solder bath for 3.5±0.5 seconds. • Minimum 95% of immersed terminal shall be covered with new uniform solder.
		Items Conditions
		1 Solder Sn-3.0Ag-0.5Cu
		2 Flux Approximately 25wt% methanol(JIS K 8891) solution of resin(JIS K 5902).

E0-R-4-014 Rev. E Page 2

G83270025

VER. A 16-Jun-16



G83270025

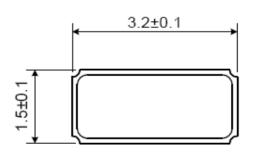
VER. A

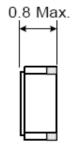
16-Jun-16

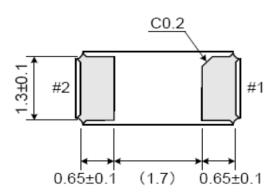
Marking



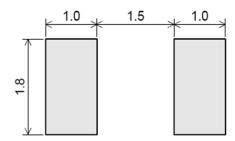
Dimensions (Units: mm)



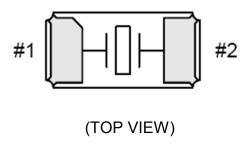




Recommended Soldering Pattern



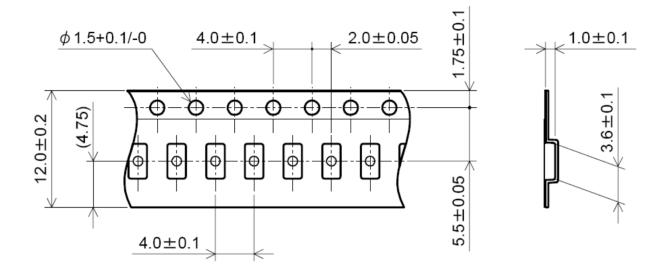
Internal connection



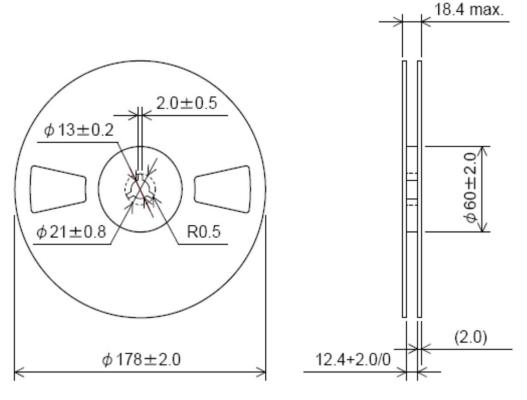
G83270025

VER. A 16-Jun-16

TAPING (Units: mm)



REEL (Units: mm)



Quantity: 3000pcs / Reel

E0-R-4-014 Rev. E Page 5